

SOLUTION DERIVED LEAD- FREE $(\text{Bi}_{0.5}\text{Na}_{0.5})\text{TiO}_3$ – BaTiO_3 (BNBT) THIN FILMS IN THE PROXIMITY OF THE MORPHOTROPIC PHASE BOUNDARY (MPB)



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² *Departamento de Química y Edafología. Facultad de Ciencias. Universidad de Navarra. 31080 – Pamplona, Navarra. Spain.*



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- 1. Objectives**
- 2. Introduction**
- 3. Experimental procedure**
- 4. Results and discussion**
- 5. Conclusions**



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1. Objectives



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- The main goal of this work is the study of lead-free ferroelectric oxides based on the **(1-x)(Bi_{0.5}Na_{0.5})TiO₃-xBaTiO₃ (BNBT)** system to replace the well known Pb(Zr_xTi_{1-x})O₃ (PZT) and the manufacturing of these materials as thin films for its integration in microelectronic devices.



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1. Objectives

Solution derived lead-free BNBT thin films

13.2.2003

EN

Official Journal of the European Union

L 37/19

DIRECTIVE 2002/95/EC OF THE EUROPEAN PARLIAMENT AND OF THE COUNCIL of 27 January 2003

on the restriction of the use of certain hazardous substances in electrical and electronic equipment

'ROHs'
Directive

1. Member States shall ensure that, from 1 July 2006, new electrical and electronic equipment put on the market does not contain lead, mercury, cadmium, hexavalent chromium, polybrominated biphenyls (PBB) or polybrominated diphenyl ethers (PBDE). National measures restricting or prohibiting the use of Applications of lead, mercury, cadmium and hexavalent chromium, which are exempted from the requirements
— lead in electronic ceramic parts (e.g. piezoelectric devices).

Lead-free compositions to substitute lead based- on compositions (PZT)

Actual trends on the manufacturing of thin films

Integration of ferroelectric materials in the information technologies (ITRS 2011)

Preparation of thin films



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2. Introduction

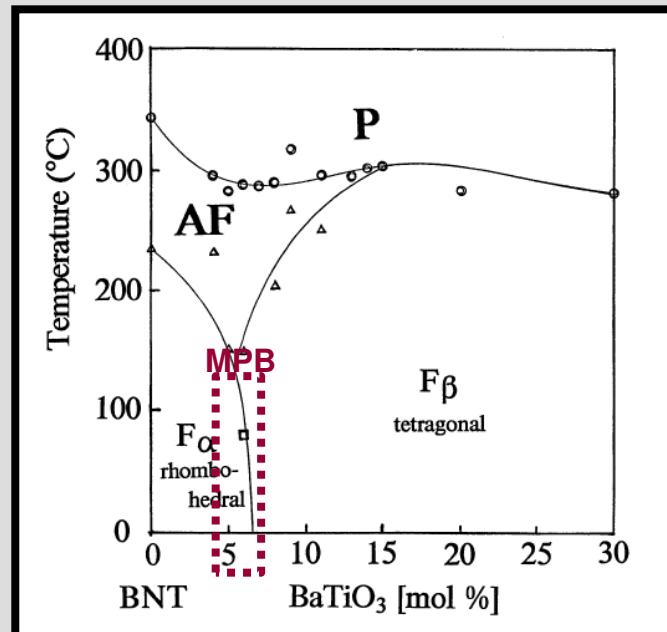


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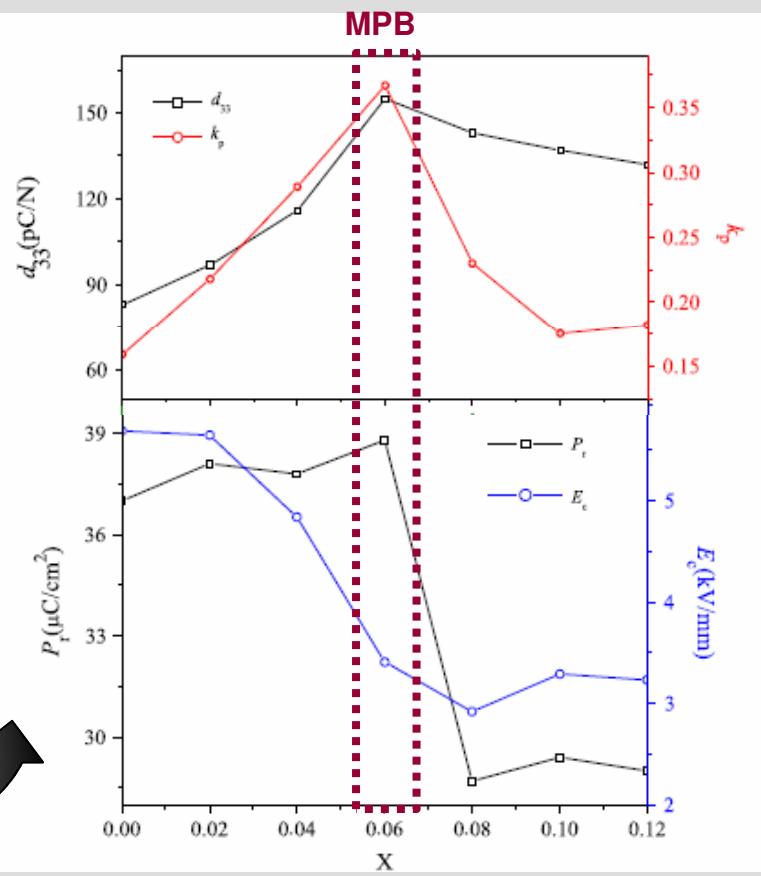
$(1-x)(\text{Bi}_{0.5}\text{Na}_{0.5})\text{TiO}_3\text{-}x\text{BaTiO}_3$ (BNBT)
Solid solution

BNT-BT
Phase diagram



Takenaka et al. Jpn J Appl Phys 1991; 30: 2236-39

Morphotropic phase boundary(MPB)



Thomas et al. Solid State Sci 2008; 10:934-940



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2. Introduction

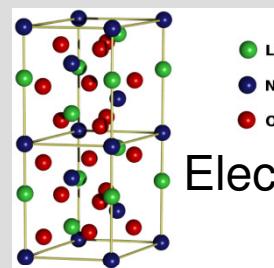
Solution derived lead-free BNBT thin films

Towards the miniaturization of ferroelectric materials and their integration into microelectronic devices

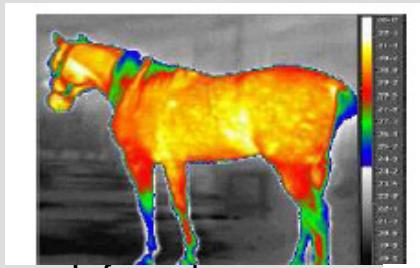
1 mm 100 µm 10 µm 1 µm 100 nm 1 nm

Bulk ceramics Thin plates Thick films Thin films Ultra-thin films Nano-sized systems

1950



Pyroelectricity



Infrared sensor

High permittivity

Electro-optic activity

Ferroelectric films

Piezoelectricity

DRAMs

Ferroelectricity

NVFRAMs



Sensors



Actuators



Bretos. Ph. D Thesis UAM 2006



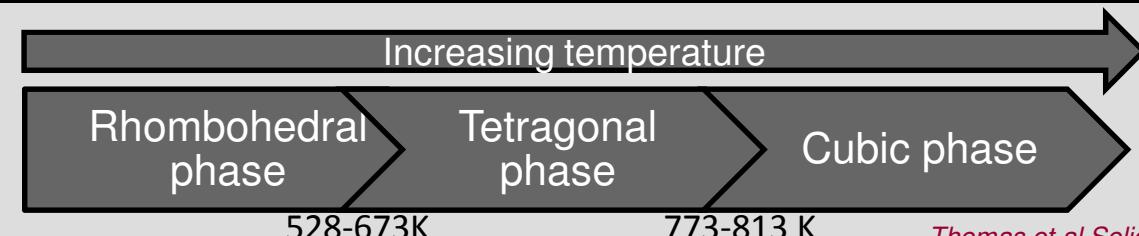
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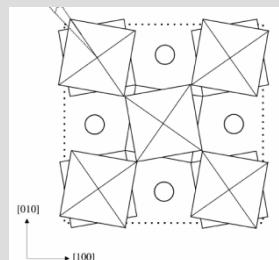
2. Introduction

Solution derived lead-free...

Bulk ceramic
 $\text{Bi}_{0.5}\text{Na}_{0.5}\text{TiO}_3$

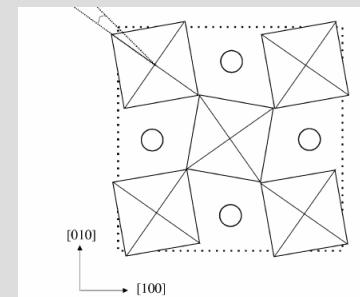
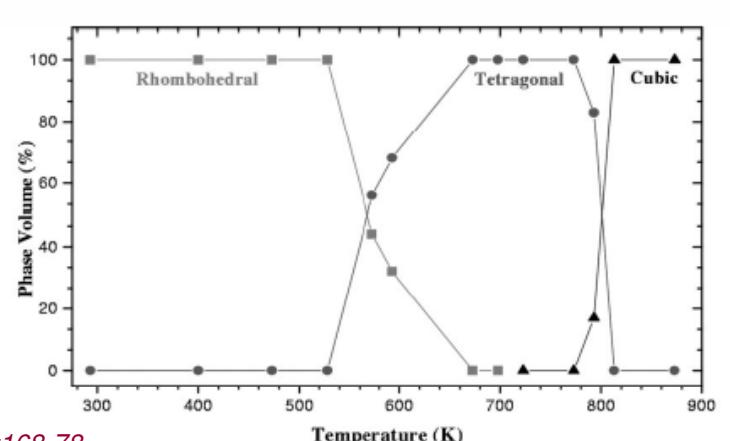


Thomas et al. Solid State Science 2010; 12: 311-17



Rhombohedral

Jones et al. Acta Crystallogr B 2002; B58:168-78



Tetragonal

Jones et al. Acta Crystallogr B 2000; B56:426-30

Single-crystal
 X-ray
 diffraction



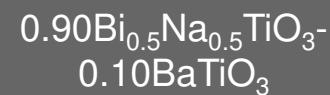
Rhombohedral phase
 with tetragonal
 inclusions

Thomas et al. Solid State Science 2010; 12: 311-17



Tetragonal

Thin film



Displacement of the
 MPB composition

The reason
 could be

Structural effects

Cheng et al. Appl Phys Lett 2004; 85: 2319-21
 Bretos et al. Mater Lett 2011; 65:2714-2716



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3. Experimental Procedure



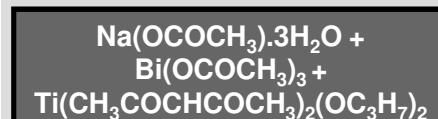
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3. Experimental procedure

Solution derived lead-free BNBT thin films

Metallic precursor



Solvents



10.0 mol% of Bi(III) excess +
10.0 mol% of Na(I) excess

Molar ratios
1.0:10.0 of Ti (IV) to
any solvents

Metallic precursor

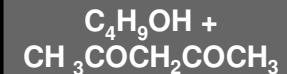


Reflux in air for 2 h

Metallic precursor



Solvents



Stirring at room
temperature

Reflux in air for 8 h



$\text{Bi}_{0.5}\text{Na}_{0.5}\text{TiO}_3$
Precursor sol
($\approx 0.60 \text{ mol L}^{-1}$)

Solvents



Stirring at room
temperature



BaTiO_3
Precursor solution
($\approx 0.30 \text{ mol L}^{-1}$)

Alonso et al. J Am Ceram Soci 2008; 92 [10]: 2218-25

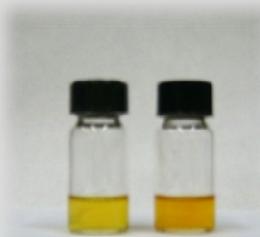
Hoffmann el al. J Eur Ceram Soci 1999: 19 ;1339-1343

$\text{Bi}_{0.5}\text{Na}_{0.5}\text{TiO}_3\text{-BaTiO}_3$
Precursor solution
($\approx 0.60 \text{ mol L}^{-1}$)

Solvent



$\text{Bi}_{0.5}\text{Na}_{0.5}\text{TiO}_3\text{-}$
 BaTiO_3
Precursor solution
($\approx 0.20 \text{ mol L}^{-1}$)



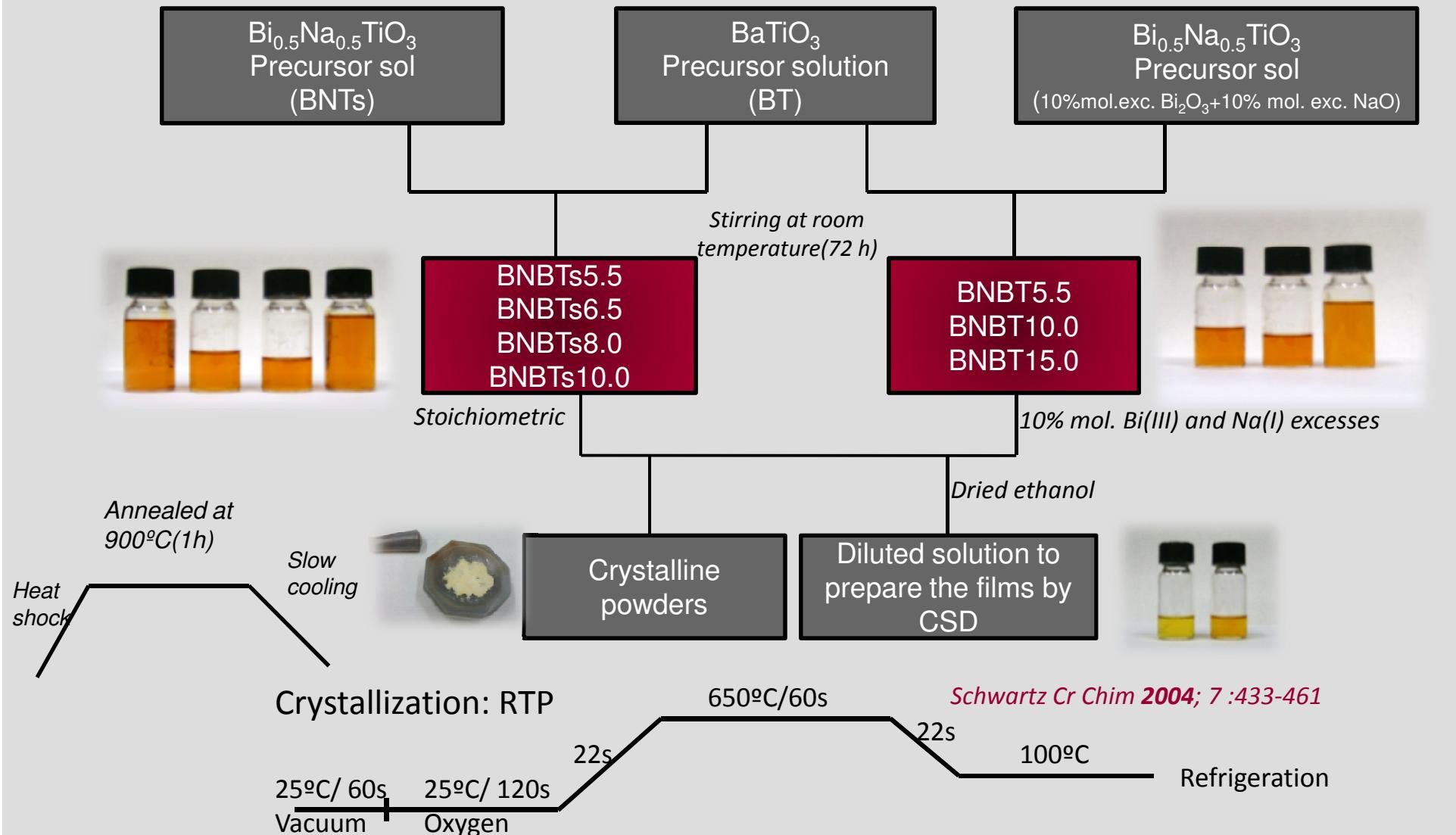
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3. Experimental procedure

Solution derived lead-free BNBT thin films

Composition in the vicinity of the MPB



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4. Results and discussion



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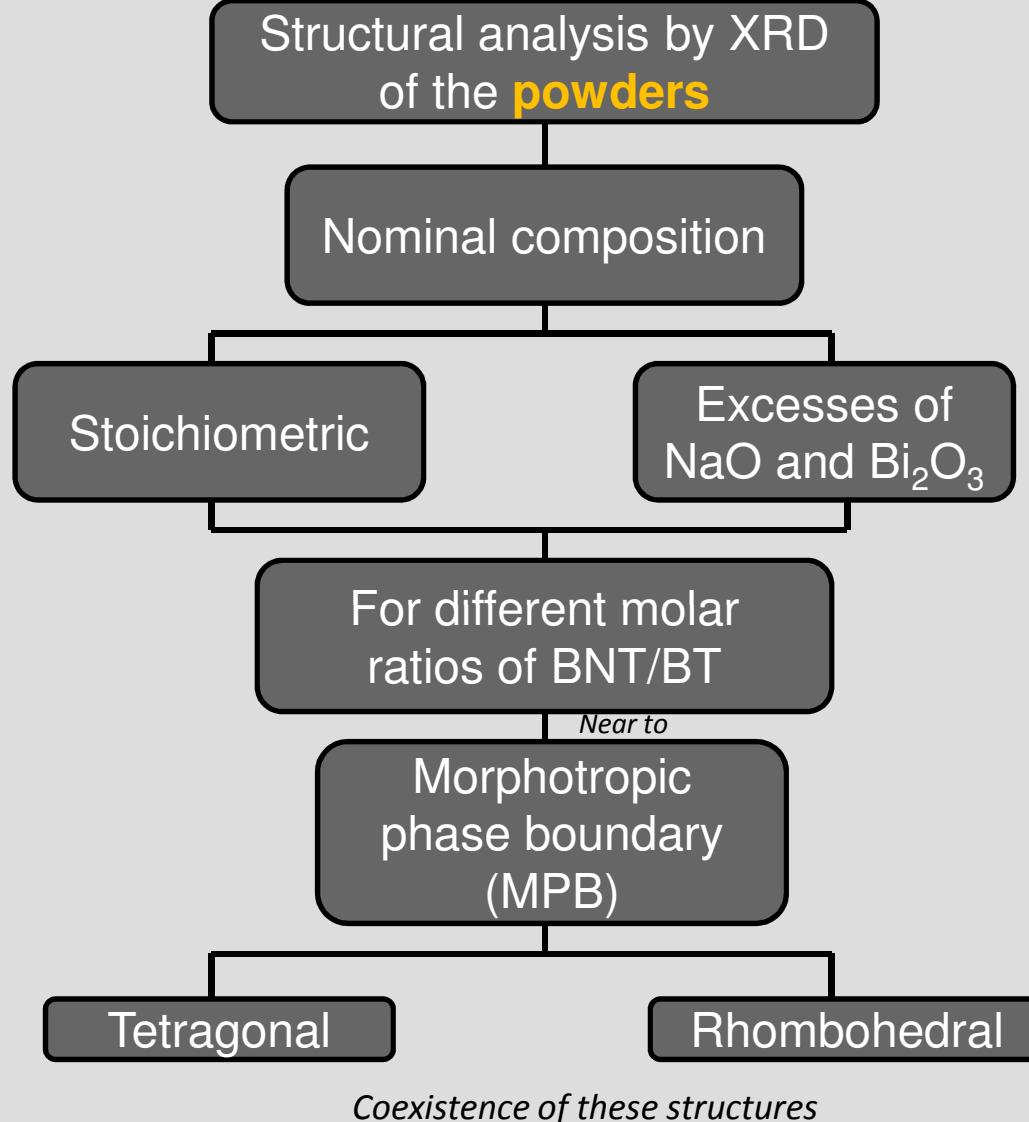


4.1 Crystalline powders



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Takenaka et al. *Jpn J Appl Phys* 1991; 30: 2236-39

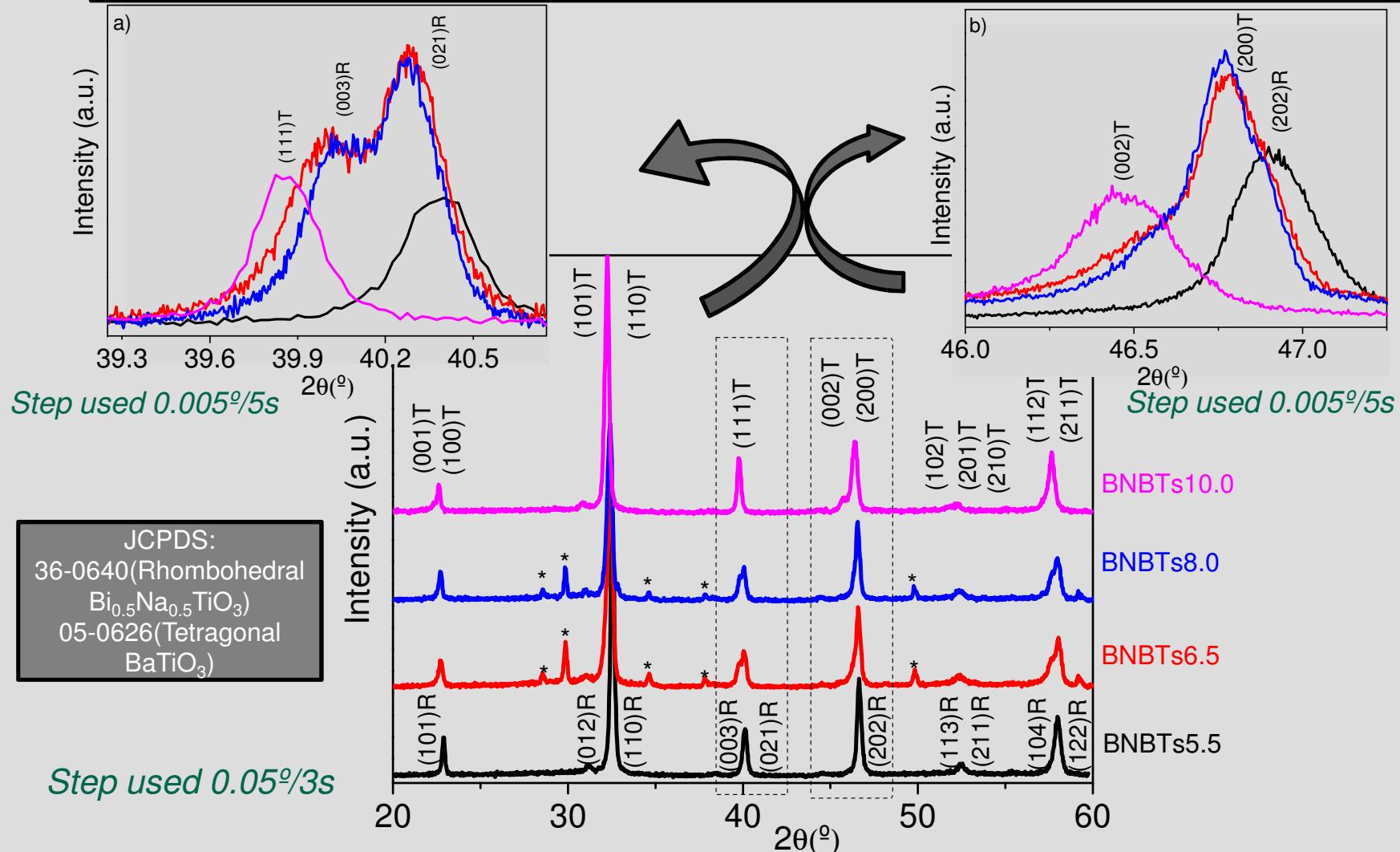


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Structural analysis of the crystalline phase in the **stoichiometric powders** with different BNBT/BT molar ratios



Jones et al. *Acta Crystallogr B* 2000; **B56**:426-30
 Jones et al. *Acta Crystallogr B* 2002; **B58**:168-78



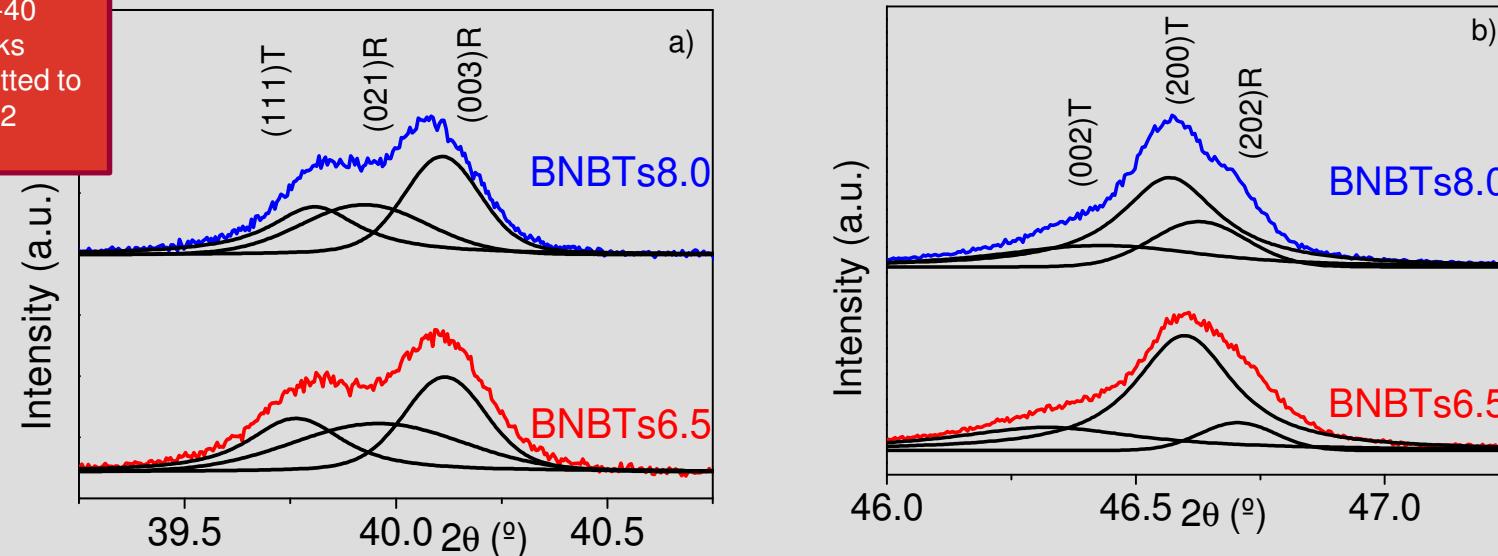
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Deconvolution has been made using program V1-40 and the peaks have been fitted to seudo-voigt 2 function

Structural analysis of crystalline **stoichiometric powders** for different BNT/BT molar ratios



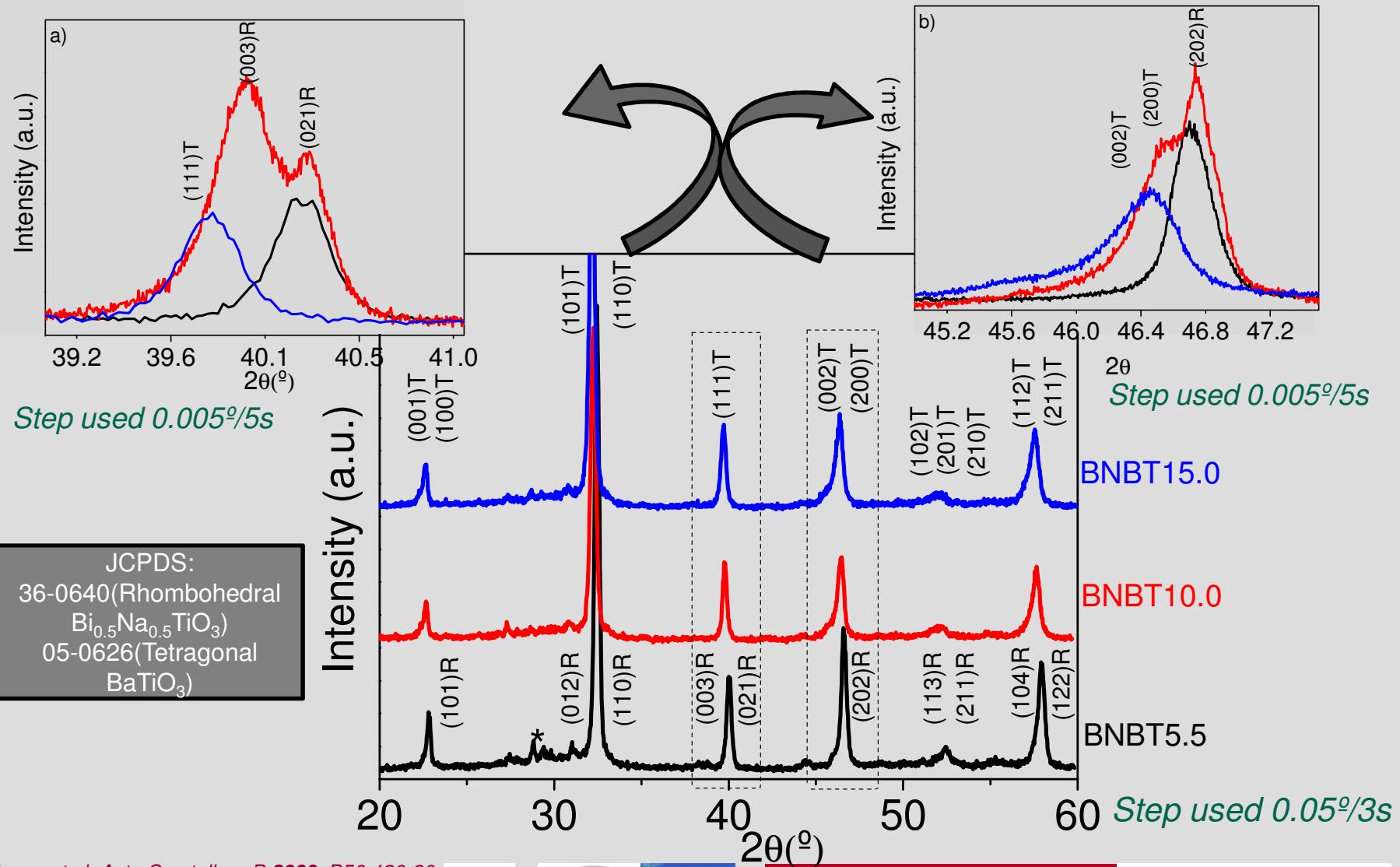
SAMPLES	MOLAR RATIOS BNT/ BT	NOMINAL COMPOSITION (stoichiometric)	CRYSTALLINE STRUCTURES OBTAINED FROM XRD PATTERNS
BNBTs5.5	94.5/5.5	$(\text{Bi}_{0.5}\text{Na}_{0.5})_{0.945}\text{Ba}_{0.055}\text{TiO}_3$	Rhombohedral
BNBTs6.5	93.5/6.5	$(\text{Bi}_{0.5}\text{Na}_{0.5})_{0.935}\text{Ba}_{0.065}\text{TiO}_3$	Rhombohedral + tetragonal (MPB)
BNBTs8.0	92.0/8.0	$(\text{Bi}_{0.5}\text{Na}_{0.5})_{0.920}\text{Ba}_{0.080}\text{TiO}_3$	Rhombohedral + tetragonal (MPB)
BNBTs10.0	90.0/10.0	$(\text{Bi}_{0.5}\text{Na}_{0.5})_{0.900}\text{Ba}_{0.100}\text{TiO}_3$	Tetragonal



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Structural analysis of the **crystalline powders** containing **excesses of Na(I) and Bi(III)**

Jones et al. *Acta Crystallogr B* 2000; B56:426-30
 Jones et al. *Acta Crystallogr B* 2002; B58:168-78



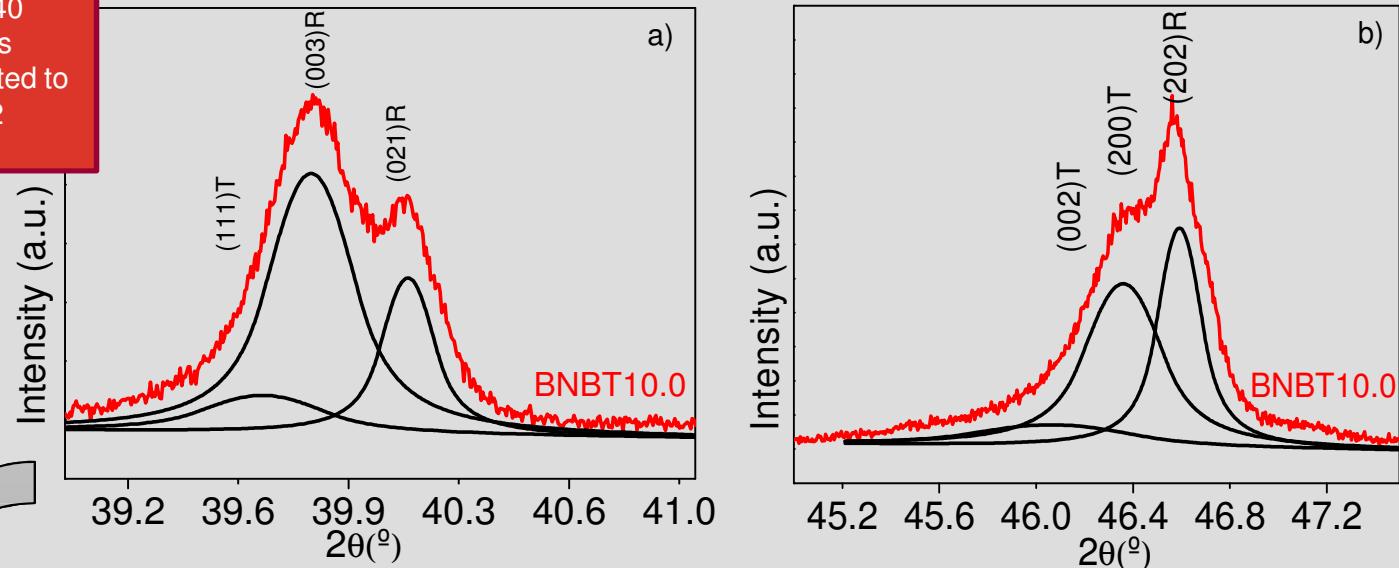
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Deconvolution has been made using program V1-40 and the peaks have been fitted to seudo-voigt 2 function

Structural analysis of crystalline powders with excesses of Na(I) and Bi(III) for different BNBT/BT molar ratios



SAMPLE	MOLAR RATIOS BNBT/BT	NOMINAL COMPOSITION (10% molar exceso Bi_2O_3 + 10% molar exceso NaO)	CRYSTALLINE STRUCTURE OBTAINED FROM XRD PATTERNS
BNBT5.5	94.5/5.5	$(\text{Bi}_{0.5}\text{Na}_{0.5})_{0.945}\text{Ba}_{0.055}\text{TiO}_3$	Rhombohedral
BNBT10.0	90.0/10.0	$(\text{Bi}_{0.5}\text{Na}_{0.5})_{0.900}\text{Ba}_{0.100}\text{TiO}_3$	Rhombohedral+ tetragonal (MPB)
BNBT15.0	85.0/15.0	$(\text{Bi}_{0.5}\text{Na}_{0.5})_{0.850}\text{Ba}_{0.150}\text{TiO}_3$	Tetragonal



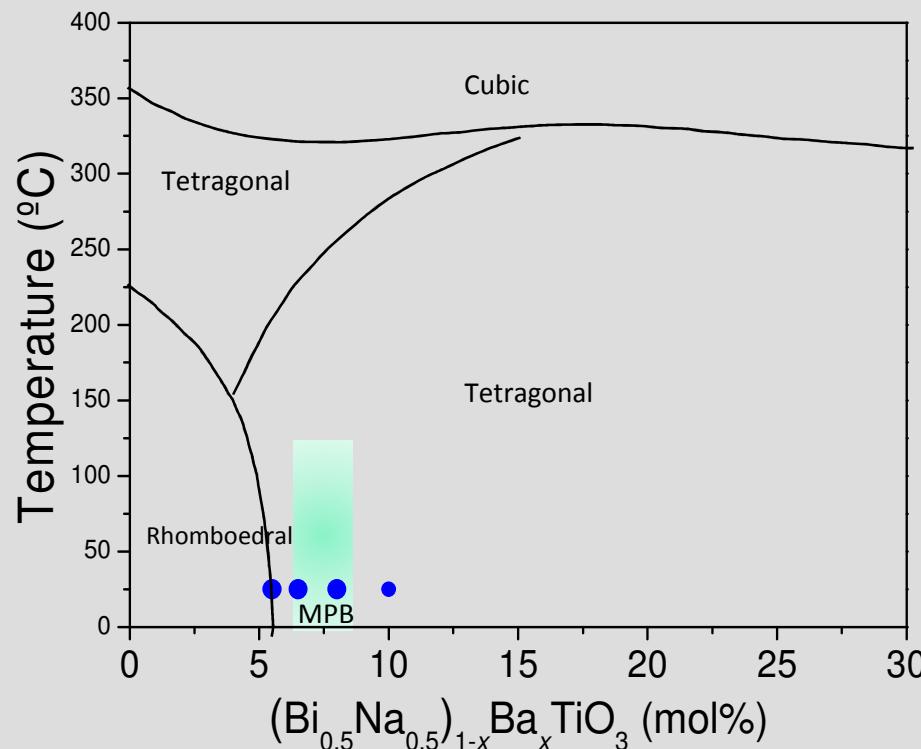
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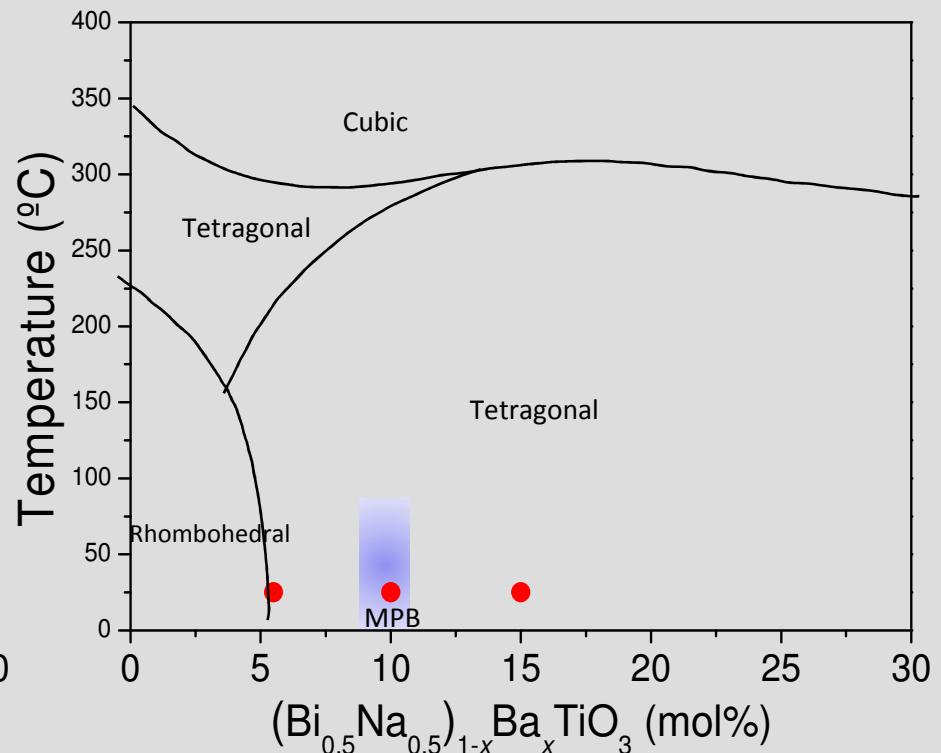
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Determination of the morphotropic phase boundary (MPB) for the **crystalline powders**

Stoichiometric nominal composition



Nominal composition containing excesses of Na(I) + Bi(III)



Rout et al. J Ceram Soc Jpn 2009; 117 [7]: 797-800

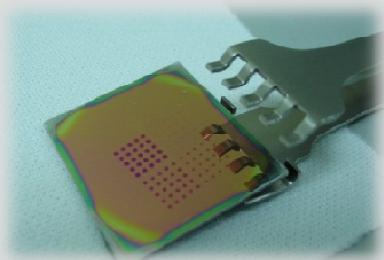


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4.2 Thin films



Ferroelectric system in thin film form:

- Lost by volatilization of Na(I)+Bi(III)
- Change of the phase because of structural effects induced by the substrate

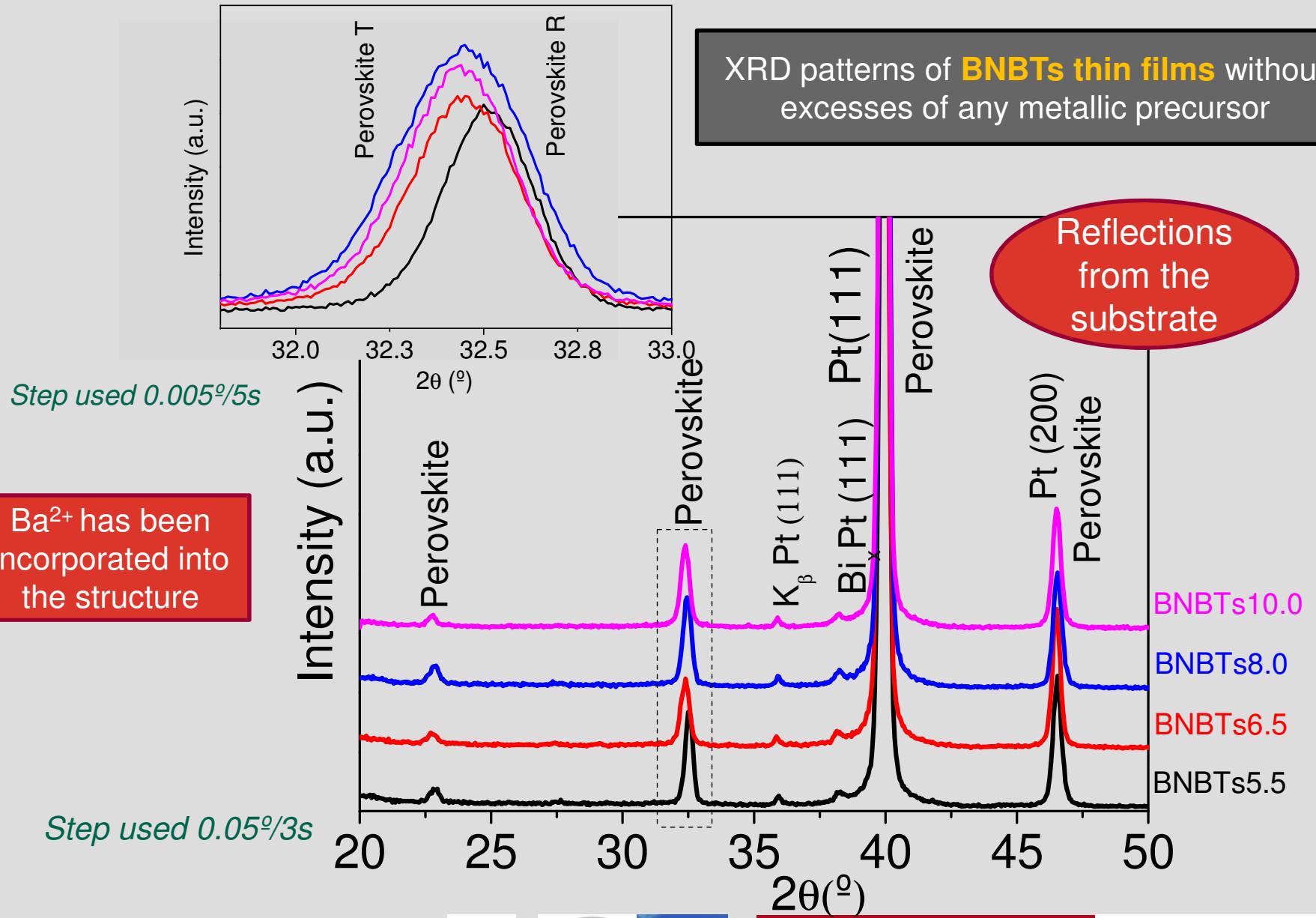


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4. Results and discussion

Solution derived lead-free BNBT thin films



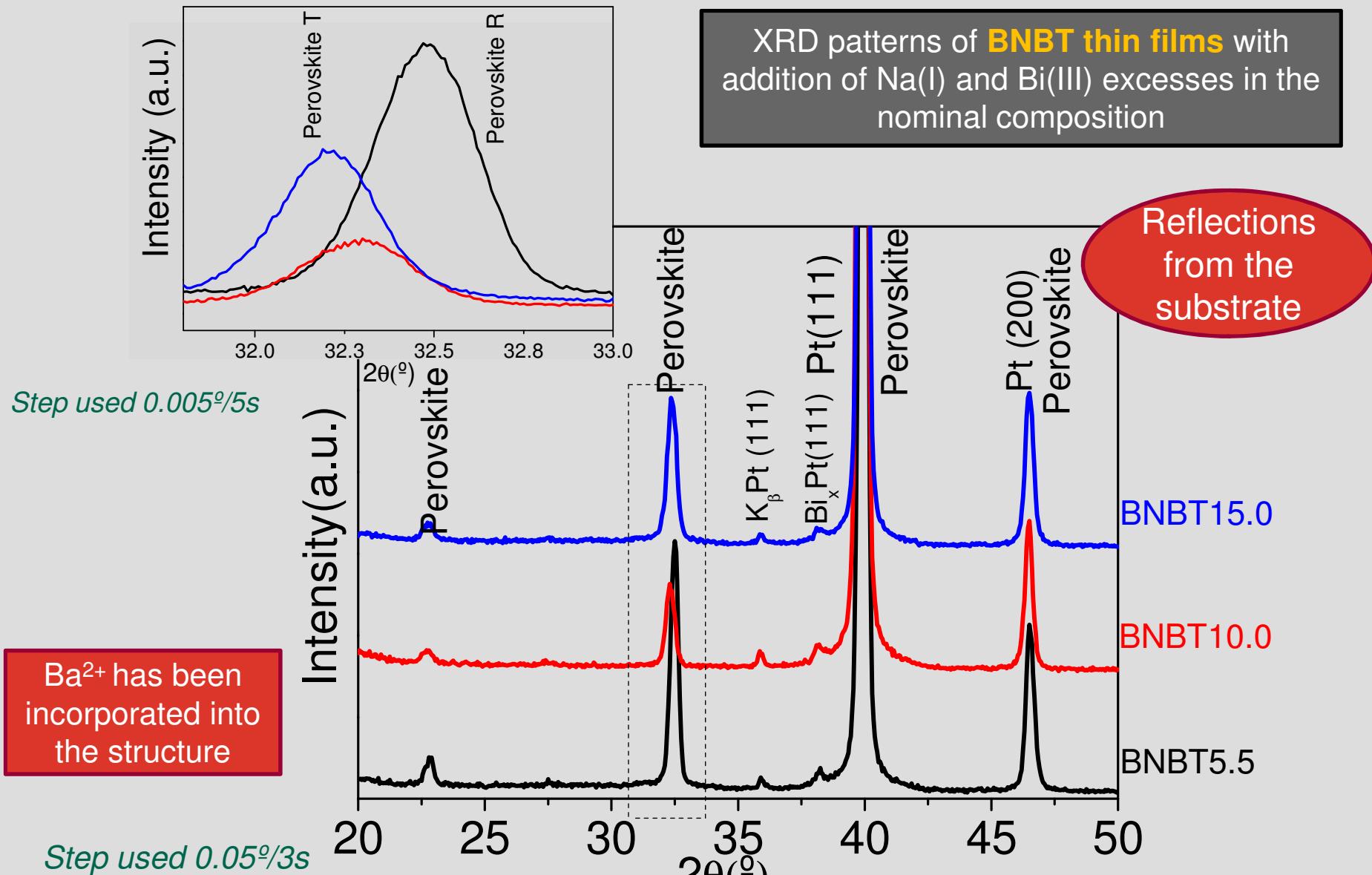
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4. Results and discussion

Solution derived lead-free BNBT thin films



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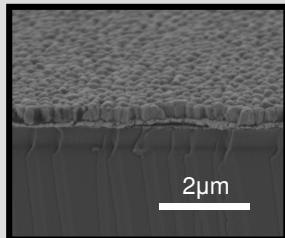
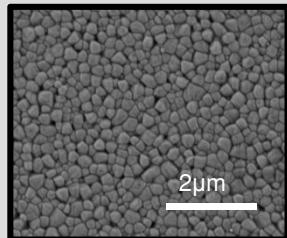


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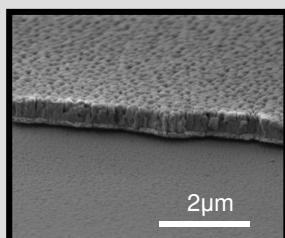
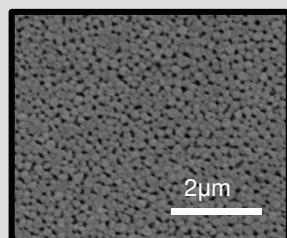
4. Results and discussion

Solution derived lead-free...

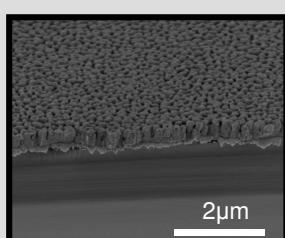
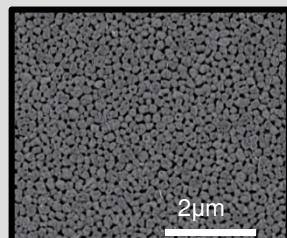
Cross-section and plan-view images of BNBTs nominal stoichiometric films



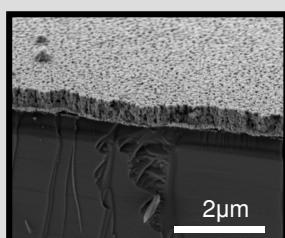
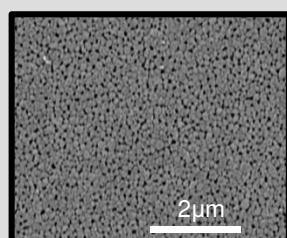
BNBTs5.5



BNBTs6.5

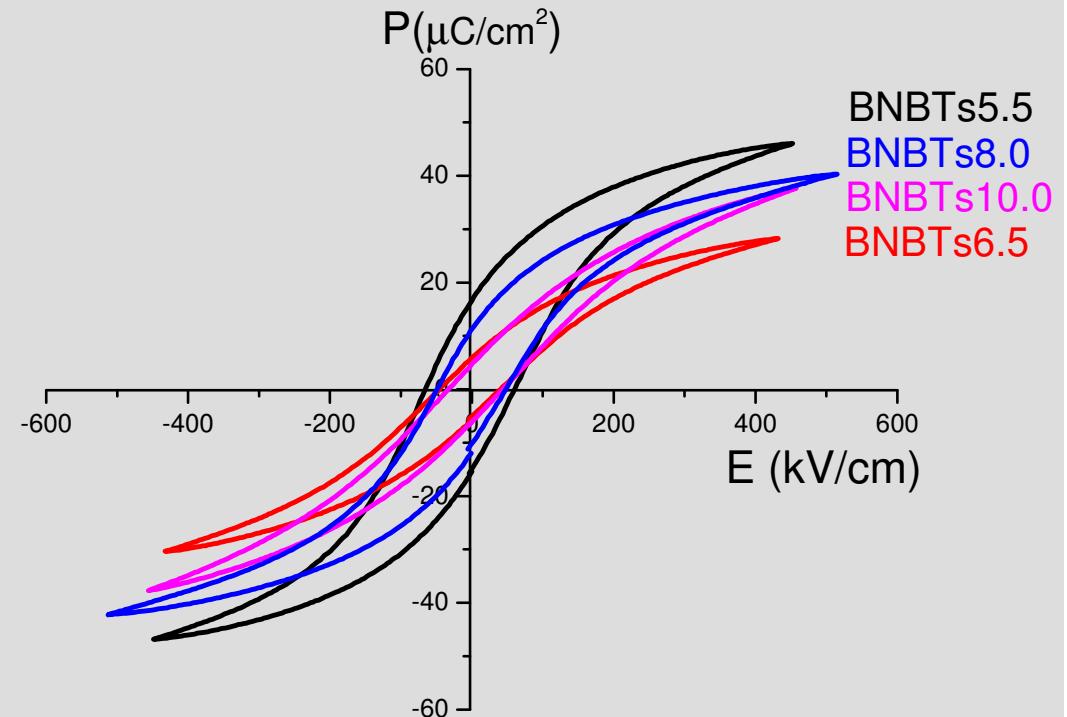


BNBTs8.0



BNBTs10.0

Electrical measurement of BNBTs nominal stoichiometric thin films



Sample	BNBTs5.5	BNBTs6.5	BNBTs8.0	BNBTs10.0
Grain size	$\approx 288 \text{ nm}$	$\approx 194 \text{ nm}$	$\approx 179 \text{ nm}$	$\approx 119 \text{ nm}$
Thickness	$\approx 341 \text{ nm}$	$\approx 459 \text{ nm}$	$\approx 329 \text{ nm}$	$\approx 435 \text{ nm}$



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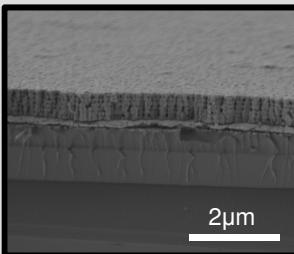
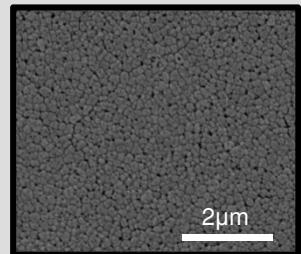


4. Results and discussion

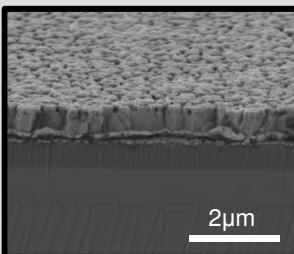
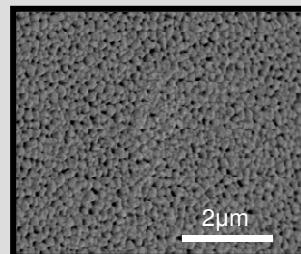
Solution derived lead-free BNBT thin films

Cross-section and plan-view images of
BNBT films containing excesses of
Na(I)+Bi(III) in the nominal composition

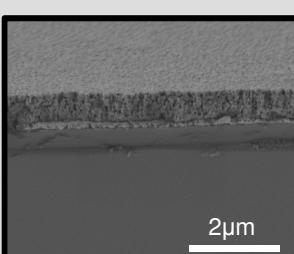
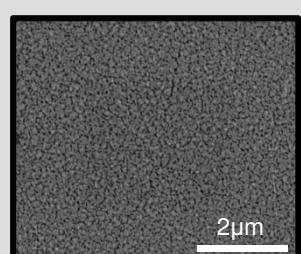
Electrical measurement of **BNBT thin films with**
Na(I)+Bi(III) excesses in the nominal composition



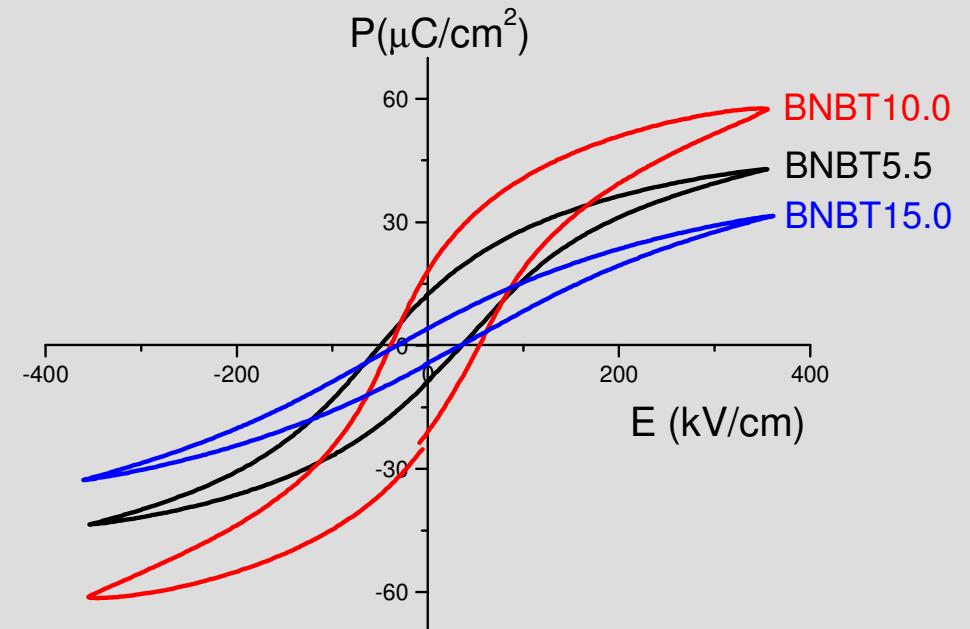
BNBT5.5



BNBT10.0



BNBT15.0



Sample	BNBT5.5	BNBT10.0	BNBT15.0
Grain size	≈ 153 nm	≈ 170 nm	≈ 97 nm
Thickness	≈ 559 nm	≈ 553 nm	≈ 550 nm

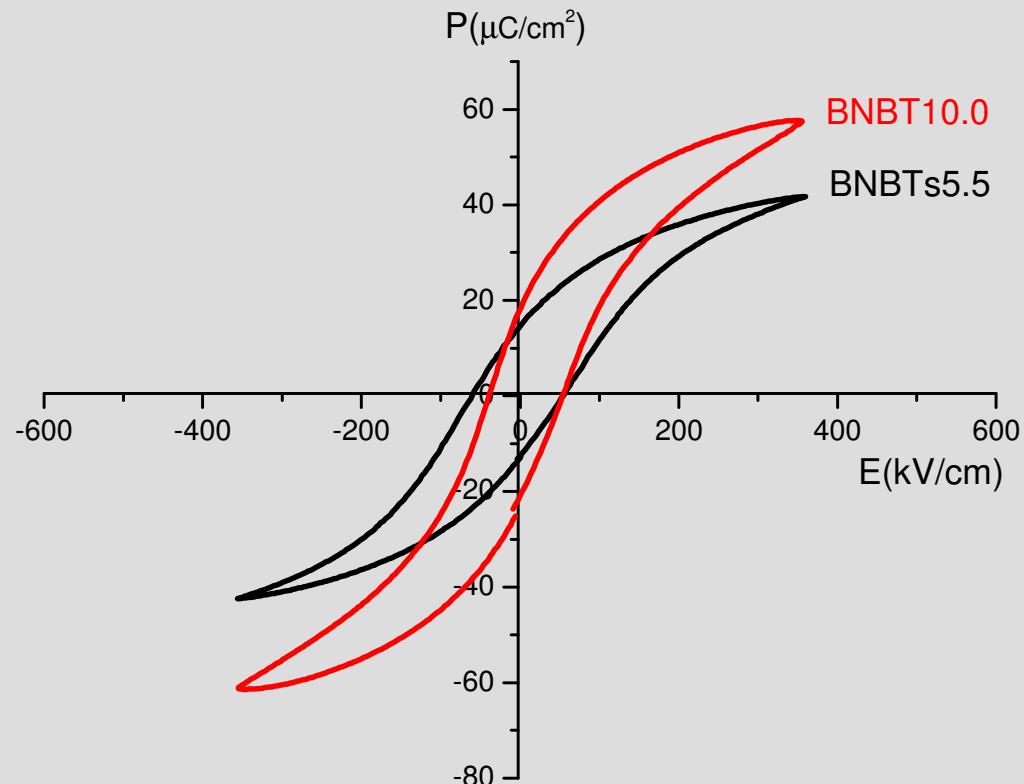


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Electrical measurements comparison between the best stoichiometric and the best not stoichiometric **films**



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5. Conclusions



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- The morphotropic phase boundary (MPB) of **BNBT powders** has been situated for 93.5/6.5 and 92.0/8.0 ‘stoichiometric’ nominal composition. Addition of Na(I) and Bi(III) excesses to the system leads to a shift of the MPB for these powders to the 90.0/10.0 nominal composition.
- The best ferroelectric response for **BNBT films** has been obtained for the 90.0/10.0 composition with addition of Na(I) and Bi(III) excesses to the respective precursor solution (P_r , 23 $\mu\text{C}/\text{cm}^2$ and $P_s \approx 60 \mu\text{C}/\text{cm}^2$), the composition for which has identified the MPB in the crystalline powders.
- Studies are in progress to elucidate the either **intrinsic** (e.g. compositional effects) or **extrinsic** (e.g. scaling effects) driving nature of the boundary displacement observed in these BNBT films with respect to bulk counterparts.



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¹ *Laboratoire de Cristallographie et Sciences des Matériaux (CRISMAT). Ecole Nationale Supérieure d'Ingénieurs de Caen (ENSICAEN). Université de Caen. 14050 – Caen. France.*

² *Departamento de Química y Edafología. Facultad de Ciencias. Universidad de Navarra. 31080 – Pamplona, Navarra. Spain.*



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